

Search Notes

Application/Control No.

10/537,470

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under
Reexamination

YANO ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	284	3/27/2007	HN
330	124R	3/27/2007	HN
330	295	3/27/2007	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	3/20/2007	HN